## ne<mark>x</mark>peria

## **Quarterly Reliability Monitoring Results**

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V.		PMEG4030EXE						
Name of Laboratory Assembly reliability labs Test		Part Description						
		Nexperia DHAM	Schottky					
		SMD package						
		Test Conditions Duration # Lots # Quantity # Rej						
	TEST							
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# 2	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, $Vr = 100%$ of max. datasheet						
# 5	Bias	reverse voltage <sup>[1]</sup>	1000 hours	206	9320	0		
	TC	JESD22-A104						
# 7	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	500 cycles	311	14080	0		
	UHAST	JESD22-A118						
# 8 <b>or</b>	Unbiased HAST	Tamb = $130 ^{\circ}$ C, RH = $85 ^{\circ}$	– 96 hours	311	14080	0		
	Unblased TAST							
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
# 8a	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$						
# 8a	Autoclave							
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = $85 ^{\circ}$ C, RH = $85\%$ , VR = $80\%$ of						
# 9		rated reverse voltage <sup>[1], [2]</sup>	1000 hours	311	14080	0		
		MIL-STD-750 Method 1037	1000 110015	511	11000	v		
	IOL	ton = toff, devices powered to insure $\Delta T_j$ =						
# 10	Intermittent Operating Life		333 hours	312	14120	0		
10			555 110013	512	11120	0		
	RSH	JESD22-A111						
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0		
	SD							
# 21	Solderability	J-STD-002		222	6660	0		

[1] The physical limitations of Schottky diodes have to be considered (thermal runaway).

[2] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab 1	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM S	Schottky	9320	0	0,46	2,19E+09

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